Features

- CRM(CQ) Super_Junction technology
- Much lower Ron*A performance for On-state efficiency
- Better efficiency due to very low FOM

Product Summary

V_{DS}	650V
$R_{DS(on),typ}$	145mΩ
I_D	19A

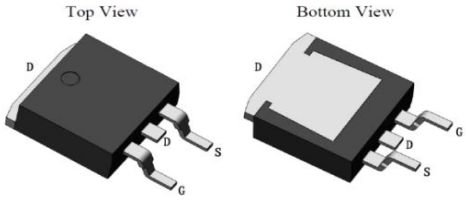
Applications

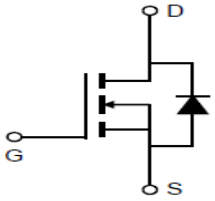
- LED/LCD/PDP TV and monitor Lighting
- Solar/Renewable/UPS-Micro Inverter System
- Charger
- Power Supply

100% DVDS Tested

100% Avalanche Tested

RoHS HF





Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRJS180N65G2	CRJS180N65G2	TO-263	Tape&Reel	N/A	N/A	1000pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	650	V
Continuous drain current [1)] T_C = 25°C T_C = 100°C	I_D	 19 12	A
Pulsed drain current [2)] (T_C = 25°C, t_p limited by $T_{j,max}$)	$I_{D,pulse}$	78	A
Avalanche energy, single pulse (L=30mH)	E_{AS}	210	mJ
MOSFET dv/dt ruggedness	dv/dt	50	V/ns
Gate-Source voltage	V_{GS}	±30	V
Power dissipation (T_C = 25°C)	P_{tot}	169	W
Continuous diode forward current(T_C = 25°C)	I_S	19	A
Diode pulse current [2)] (T_C = 25°C)	$I_{S,pulse}$	78	A
Recovery diode dv/dt [3)]	dv/dt	50	V/ns
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	°C

1) Limited by Tj,max. Maximum Duty Cycle D = 0.50;

2) Pulse width t_p limited by $T_{j,max}$

3) Identical low side and high side switch with identical R_g

Thermal Resistance

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction – case	R_{thJC}	-	0.53	0.74	°C/W	
Thermal resistance, junction – ambient	R_{thJA}	-	-	94	°C/W	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Static Characteristic						
Drain-source breakdown voltage	BV_{DSS}	650	-	-	V	V_{GS}=0V,I_D=250μA
Gate threshold voltage	$V_{GS(th)}$	3	-	4	V	V_{DS}=V_{GS},I_D=250μA
Zero gate voltage drain current	I_{DSS}	-	-	1	μA	V_{DS}=650V,V_{GS}=0V T_j=25°C
		-	1	-		T_j=150°C
Gate-source leakage current	I_{GSS}	-	-	±100	nA	V_{GS}=±30V,V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	-	145	180	mΩ	V_{GS}=10V,I_D=10A, T_j=25°C
		-	360	-		T_j=150°C
Transconductance	g_{fs}	-	14	-	S	V_{DS}=20V,I_D=10A
Dynamic Characteristic						
Input Capacitance	C_{iss}	-	1114	-	pF	V_{GS}=0V, V_{DS}=100V, f=1MHz
Output Capacitance	C_{oss}	-	68	-		
Reverse Transfer Capacitance	C_{rss}	-	0.85	-		
Gate Total Charge	Q_g	-	36	-	nC	V_{GS}=10V, V_{DS}=480V, I_D=10A
Gate-Source charge	Q_{gs}	-	7.9	-		
Gate-Drain charge	Q_{gd}	-	18	-		
Gate plateau voltage	$V_{plateau}$	-	6.1	-	V	
Turn-on delay time	$t_{d(on)}$	-	23	-	ns	V_{GS}=10V, I_D=10A, V_{DS}=400V, R_g=5Ω
Rise time	t_r	-	34	-		
Turn-off delay time	$t_{d(off)}$	-	124	-		
Fall time	t_f	-	30	-		
Gate resistance	$R_{g,int}$	-	22	-	Ω	f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	0.6	0.85	1.1	V	V_{GS}=0V,I_{SD}=10A
Body Diode Reverse Recovery Time	t_{rr}	-	348	-	ns	I_{SD}=10A di_F/dt=100A/μs V_{DS}=400V
Body Diode Reverse Recovery Charge	Q_{rr}	-	5.6	-	μC	

Typical Performance Characteristics

Fig 1. Output Characteristics (T_j=25℃)

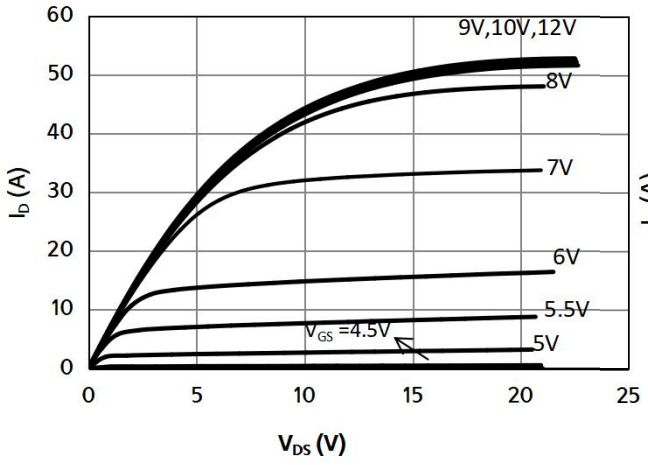


Fig 2. Output Characteristics (T_j=150℃)

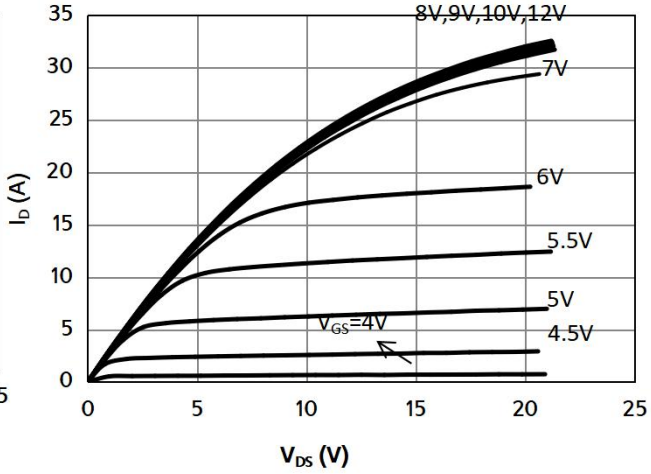


Fig 3: Transfer Characteristics

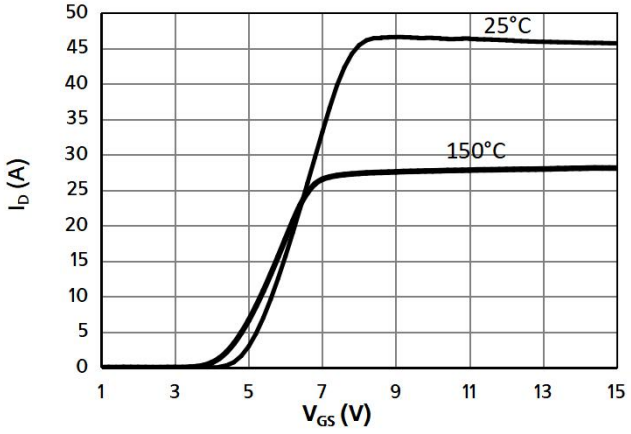


Fig 4: V_{TH} vs. T_j Temperature Characteristics

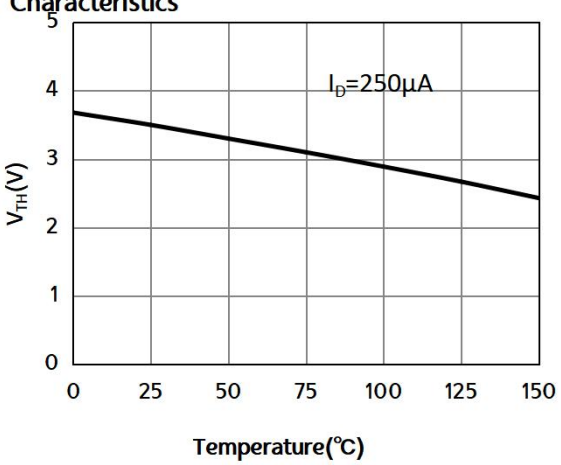


Fig 5: $R_{DS(on)}$ vs. I_{DS} Characteristics(T_j=25℃)

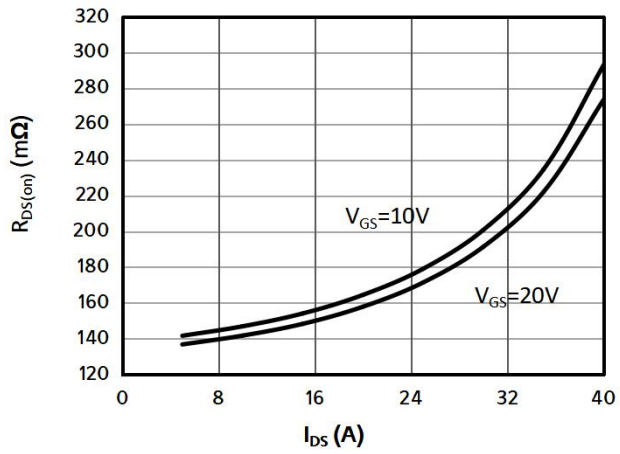


Fig 6: $R_{DS(on)}$ vs. Temperature

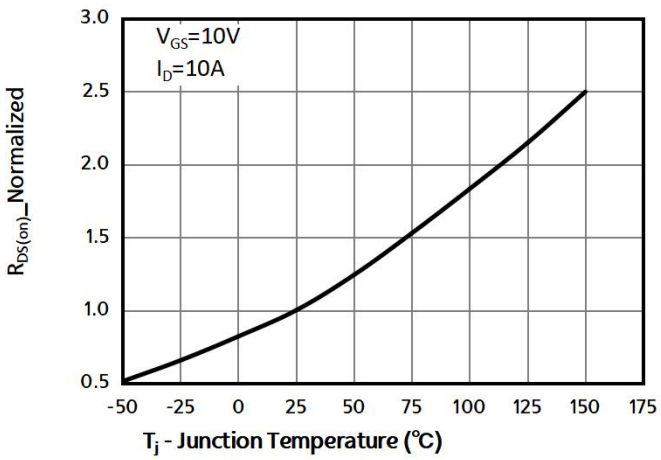


Fig 7: BV_{DSS} vs. Temperature

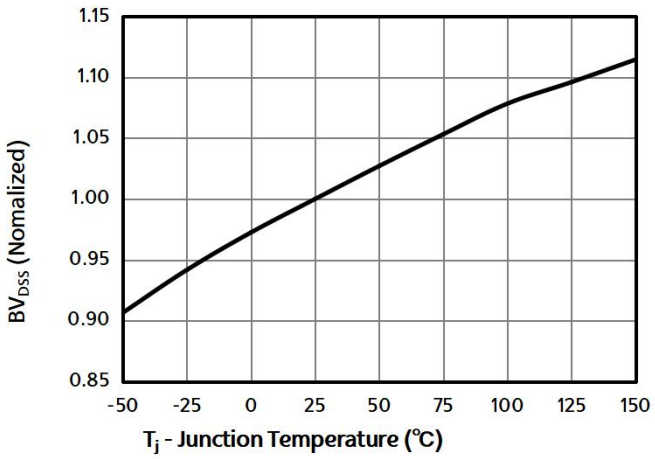


Fig 8: $R_{DS(on)}$ vs. Gate Voltage

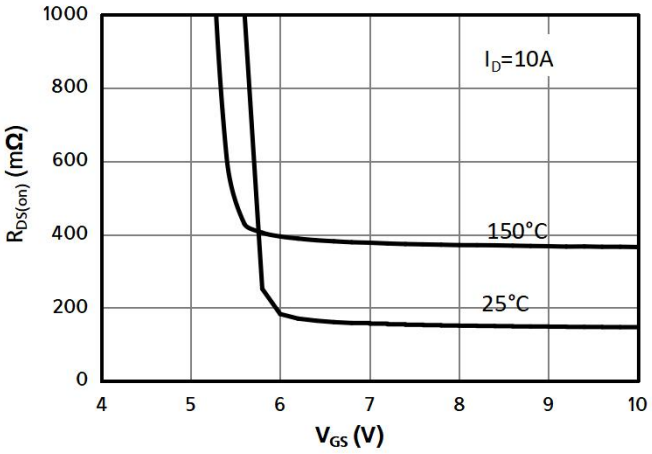


Fig 9: Body-diode Forward Characteristics

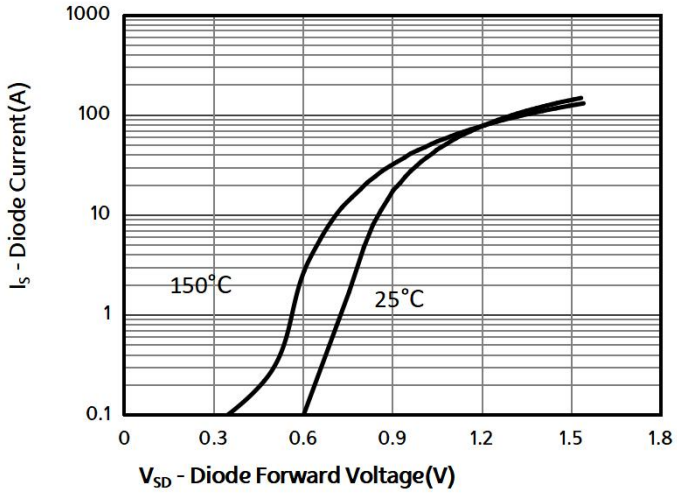


Fig 10: Gate Charge Characteristics

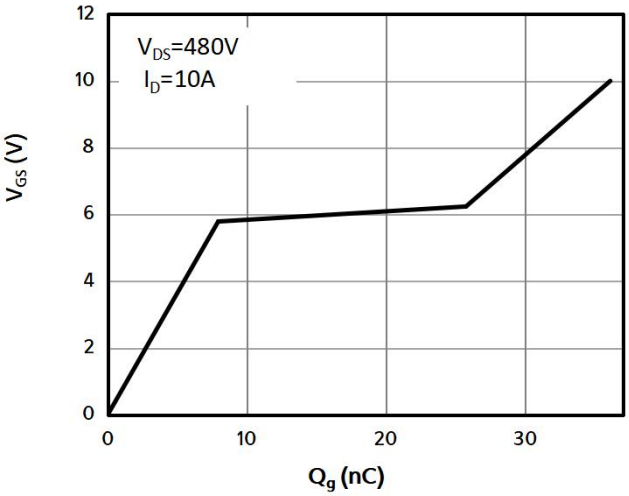


Fig 11: Capacitance Characteristics

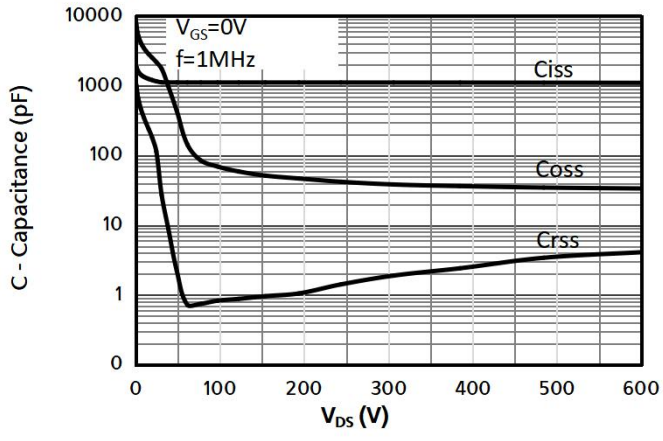


Fig 12: Safe Operating Area

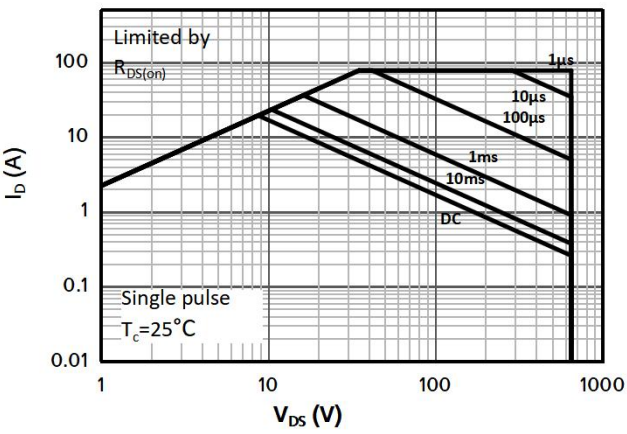
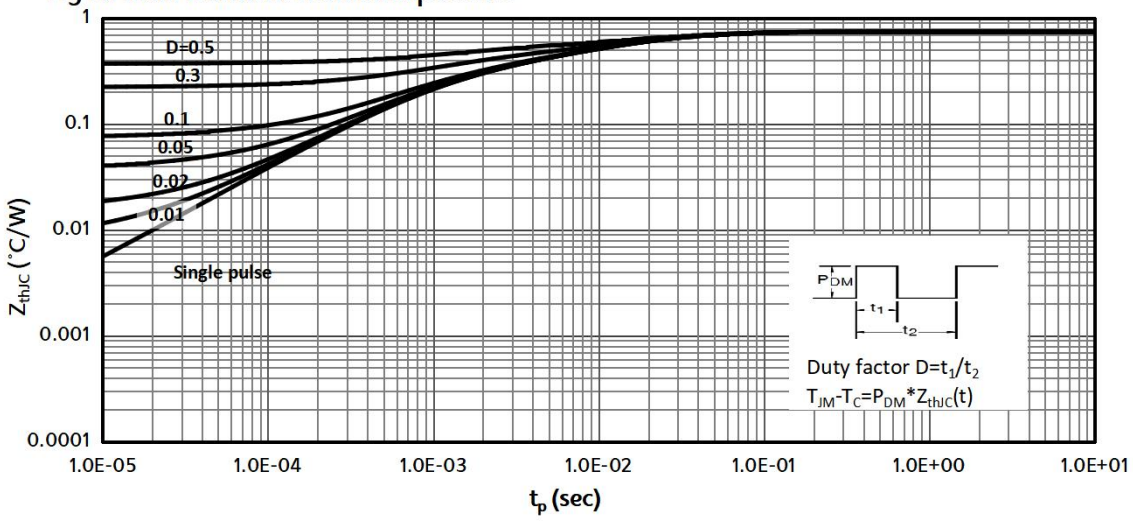
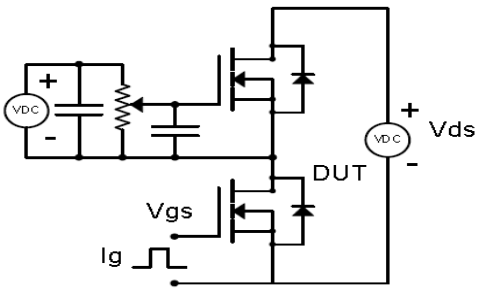


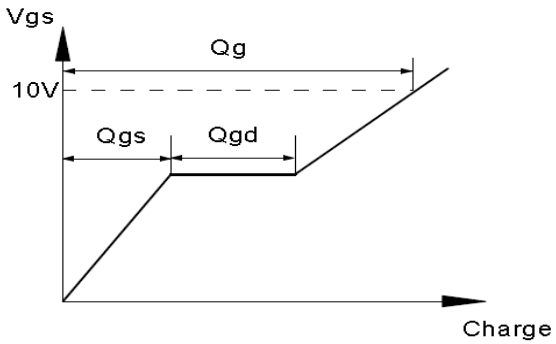
Fig 13: Max. Transient Thermal Impedance



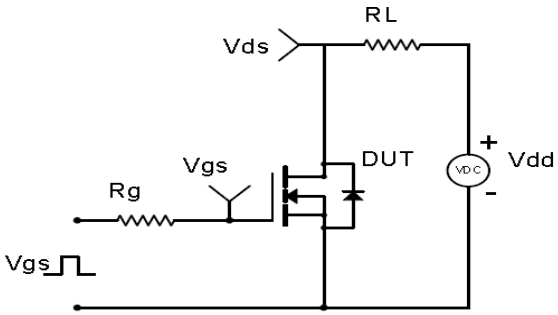
Test Circuit & Waveform

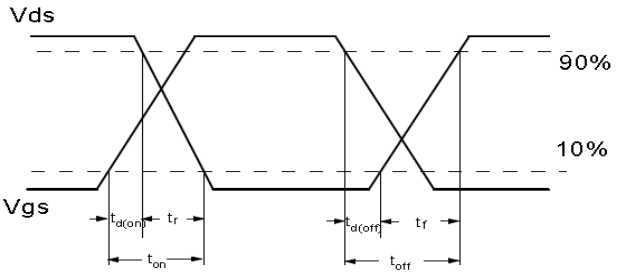
Gate Charge Test Circuit & Waveform



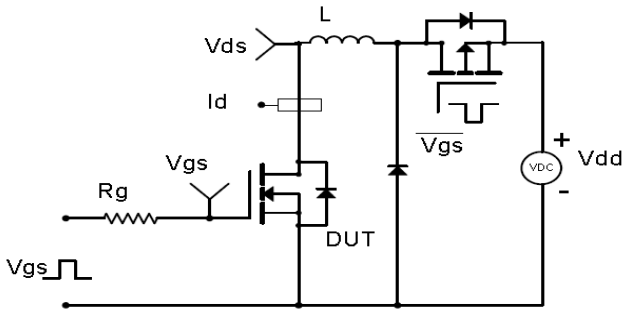


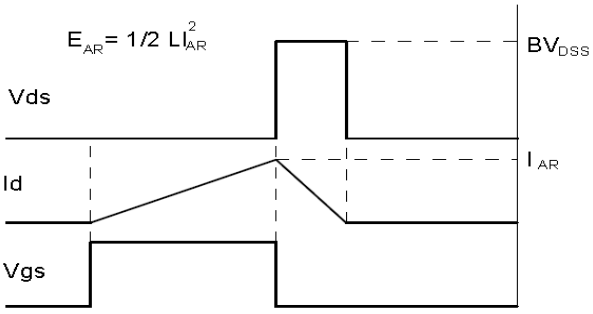
Resistive Switching Test Circuit & Waveforms



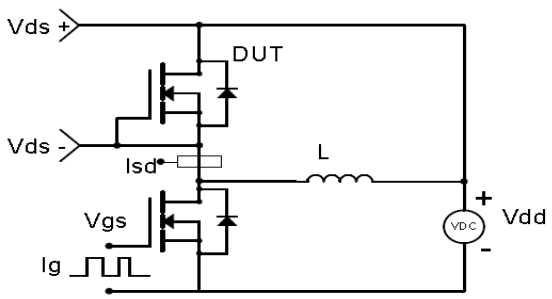


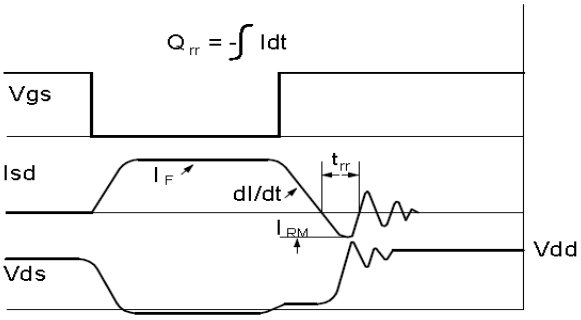
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



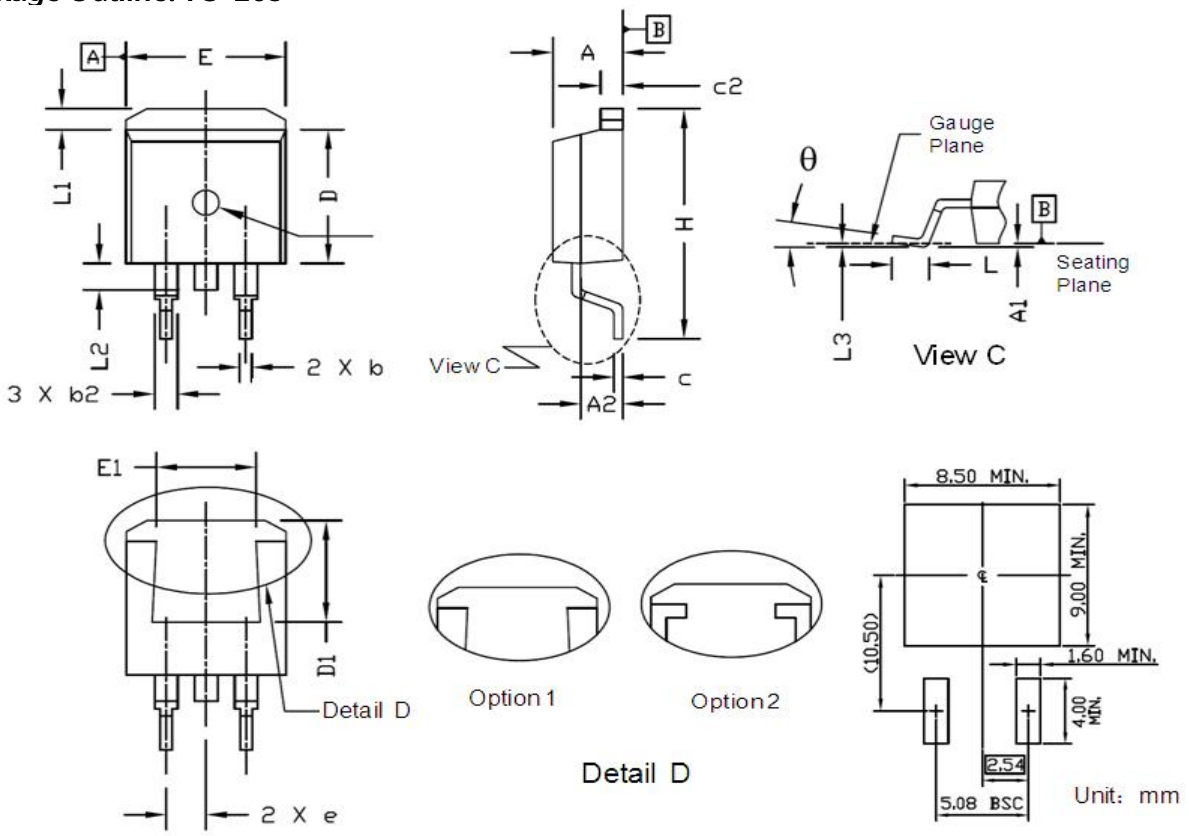


Diode Recovery Test Circuit & Waveforms





Package Outline: TO-263



Symbol		Dimensions In Millimeters		Dimensions In Inches	
		Min.	Max.	Min.	Max.
A		4.30	4.86	0.169	0.191
A1		0.00	0.25	0.000	0.010
A2		2.20	2.90	0.087	0.114
b		0.68	0.94	0.027	0.037
b2		1.14	1.78	0.045	0.070
c		0.33	0.65	0.013	0.026
c2		1.17	1.40	0.046	0.055
D		8.38	9.45	0.330	0.372
D1		6.90	8.17	0.272	0.322
e		2.54 BSC.		0.100 BSC.	
E		9.78	10.50	0.385	0.413
E1		6.50	8.60	0.256	0.339
H		14.61	15.88	0.575	0.625
L		1.78	2.79	0.070	0.110
L1		0.70	1.60	0.028	0.063
L2		1.00	1.78	0.039	0.070
L3		0.25 BSC.		0.010 BSC.	
θ	Option A	-8°	0°	-8°	0°
	Option B	0°	8°	0°	8°

Marking



NOTE:
NXBBAAAA

N	—WB code (Usually omitted)
X	—Assembly location code
BB	—Fab code
AAAA	—Lot code

Revision History

Revison	Major changes
2.0	Final version

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qulified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semicondutor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.